

A benchmark suite for evaluating the efficiency of test tools

Kruus, Helena; Ubar, Raimund-Johannes; Ellervee, Peeter; Gorev, Maksim; Pesonen, Vadim; Devadze, Sergei; Orasson, Elmet; Brik, Marina; Min, Mart; Annus, Paul; Kruus, Margus; Meigas, Kalju BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 85-88 : ill

Complementing ICT studies with learning objects on domain ontologies

Robal, Tarmo; Kruus, Helena; Kalja, Ahto Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 92-96 : ill

Defect-oriented BIST quality analysis

Kruus, Helena; Ubar, Raimund-Johannes; Raik, Jaan BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 153-156 : ill

Diagnostic modelling of digital systems with binary and high-level decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Kruus, Helena; Lensen, Harri; Evertson, Teet Progress in industrial mathematics at ECMI 2006 2008 / p. 902-907 : ill https://link.springer.com/chapter/10.1007/978-3-540-71992-2_158

Diagnostic software with WEB interface for teaching purposes

Vislogubov, Vladislav; Jutman, Artur; Kruus, Helena; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 255-258 : ill

e-Bibliotheca - a virtual library service

Robal, Tarmo; Kruus, Helena Proceedings of the Thirteenth International Conference on Information Systems Development : Advances in Theory, Practice and Education : Vilnius, Lithuania 2004 / p. 139-148

Environment for the analysis of functional self-test quality in digital systems

Ubar, Raimund-Johannes; Kostin, Sergei; Kruus, Helena; Aarna, Margit; Devadze, Sergei Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill https://artiklid.elnet.ee/record=b2673964*est <https://doi.org/10.3176/proc.2014.2.05> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Evaluation of SysML software for teaching systems engineering basics

Kruus, Helena; Jervan, Gert Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 29-32 : ill

Hardware close programming for freshmen

Kruus, Helena; Brik, Marina; Kruus, Margus; Ruberg, Priit; Viies, Vladimir; Ellervee, Peeter 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 93-96 : ill

High quality test generation for digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan Romanian journal of information science and technology 2005 / 1, p. 73-84 : ill

How to generate high quality tests for digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill <http://dx.doi.org/10.1109/SMICND.2004.1403048>

A hybrid BIST architecture and its optimization for SoC testing

Jervan, Gert; Peng, Zebo; Ubar, Raimund-Johannes; Kruus, Helena Proceedings of the 3rd International Symposium on Quality Electronic Design : ISQED 2002, March 18-21, 2002, San Jose, California 2002 / p. 273-279 : ill <https://ieeexplore.ieee.org/document/996750>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill <http://dx.doi.org/10.1109/DSD.2007.4341529>

Hybrid BIST optimization using reseeding and test set compaction

Jervan, Gert; Orasson, Elmet; Kruus, Helena; Ubar, Raimund-Johannes Microprocessors and microsystems 2008 / 5/6, p. 254-262 : ill <https://www.sciencedirect.com/science/article/abs/pii/S0141933108000288>

Infotehnoloogia rebane - milline ta on? : [esmakursuslaste arvutiteadmistest]

Kruus, Helena Arvutikasutaja 2003 / 1, lk. 6

Investigating defects in digital circuits by Boolean differential equations

Kruus, Helena; Orasson, Elmet; Robal, Tarmo; Ubar, Raimund-Johannes The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

Involving students in teaching process — encouraging student-generated content in ICT studies

Kruus, Helena; Ellervee, Peeter; Robal, Tarmo; Ruberg, Priit; Kruus, Margus Proceedings of the 24th International Conference on European Association for Education in Electrical and Information Engineering : 30-31 May 2013, Chania, Greece 2013 / p. 76-81 : ill

Laboratory framework TEAM for investigating the dependability issues of microprocessor systems

Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes; Kruus, Helena 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 80-83 : ill

Optimization of built-in self-test in digital systems = Sisseehitatud enesetestimise optimeerimine digitaalsüsteemides

Kruus, Helena 2011

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 133-136 : ill

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the IEEE 2nd International Symposium on Industrial Embedded Systems : SIES'2007 : Lisbon, Portugal, 4-6 July 2007 2007 / p. 71-77
<https://ieeexplore.ieee.org/document/4297319>

Optimization of the store-and-generate based built-in self-test

Ubar, Raimund-Johannes; Jervan, Gert; Kruus, Helena; Orasson, Elmet; Aleksejev, Igor BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 199-202 : ill

Sisseehitatud isetestimine digitaalsüsteemides

Kruus, Helena A & A 2011 / lk. 32-37 : ill https://artiklid.elnet.ee/record=b2472216*est

SysML in systems engineering course

Kruus, Helena; Robal, Tarmo; Jervan, Gert 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 177-181 : ill

Teaching modeling in SysML/UML and problems encountered

Kruus, Helena; Robal, Tarmo; Jervan, Gert Proceedings of the 25th International Conference on European Association for Education in Electrical and Information Engineering : 30 May-June 2014, Cesme, Türkiye 2014 / p. 33-36 : ill

Using Tabu Search for optimization of memory-constrained hybrid BIST

Kruus, Helena; Jervan, Gert; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / p. 85-88 : ill

Using Tabu Search for optimization of memory-constrained hybrid BIST

Kruus, Helena; Jervan, Gert; Ubar, Raimund-Johannes BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 155-158 : ill

Using Tabu search method for optimizing the cost of hybrid BIST

Kruus, Helena; Ubar, Raimund-Johannes; Jervan, Gert; Peng, Z. XVI Conference on Design of Circuits and Integrated Systems : Porto, Portugal, 2001 2001 / p. 445-450 <https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=e97bb394ff71aa0affcc5fb372404bbc246888a8>